Effect of Metal Doping and Vacancies on the Thermal Conductivity of Monolayer Molybdenum Diselenide

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\textbf{ABSTRACT:} It is well understood that defect engineering can give rise to exotic electronic properties in transition-metal dichalcogenides (TMDs), but to this date, there is no detailed study to illustrate how defects can be engineered to tailor their thermal properties. Here, through combined experimental and theoretical approaches based on the first-principles density functional theory and Boltzmann transport equations, we have explored the effect of lattice vacancies and substitutional tungsten (W) doping on the thermal transport of the suspended molybdenum diselenide (MoSe$_2$) monolayers grown by chemical vapor deposition (CVD). The results show that even though the isoelectronic substitution of the W atoms for Mo atoms in CVD-grown Mo$_{0.82}$W$_{0.18}$Se$_2$ monolayers reduces the Se vacancy concentration by 50\% compared to that found in the MoSe$_2$ monolayers, the thermal conductivity remains intact in a wide temperature range. On the other hand, Se vacancies have a detrimental effect for both samples and more so in the Mo$_{0.82}$W$_{0.18}$Se$_2$ monolayers, which results in thermal conductivity reduction up to 72\% for a vacancy concentration of 4\%. This is because the mass of the W atom is larger than that of the Mo atom, and missing a Se atom at a vacancy site results in a larger mass difference and therefore kinetic energy and potential energy difference. Furthermore, the monotonically increasing thermal conductivity with temperature for both systems at low temperatures indicates the importance of boundary scattering over defects and phonon–phonon scattering at these temperatures.

\textbf{KEYWORDS:} thermal conductivity, transition-metal dichalcogenides, molybdenum diselenide, defect engineering, vacancy, isoelectronic doping

\section*{INTRODUCTION}

The unique electronic and optoelectronic characteristics of two-dimensional (2D) transition-metal dichalcogenides (TMDs), notably MoS$_2$ and MoSe$_2$, classify them as graphene alternatives with regard to fundamental science and technological implications. These layered materials exhibit promising properties, such as indirect-to-direct bandgap crossover in the visible spectrum,\textsuperscript{1,2} highly efficient photovoltaic response,\textsuperscript{3} strong photoluminescence (PL),\textsuperscript{4–6} optically controllable valley polarization\textsuperscript{7} as well as field-induced transport with high on–off ratios.\textsuperscript{8} In addition, they have recently appeared in the horizon of thermoelectric applications, thanks to their large and tunable Seebeck coefficient.\textsuperscript{9–11} To achieve high quality for such layered materials, various techniques\textsuperscript{12–15} have been adopted among which molecular beam epitaxy\textsuperscript{16} and chemical vapor deposition (CVD)\textsuperscript{17} are more desirable because of their scalability for industrial device fabrication. However, because of the imperfection of growth processes, the monolayer TMDs synthesized by these techniques contain higher density of unintentional localized defects, such as vacancies, dislocation cores, and grain boundaries, compared with mechanically exfoliated ones from bulk crystal.\textsuperscript{18–24} Recently, isoelectronic doping has been shown to be an effective strategy to suppress the vacancy concentration, enable faster quenching of defect-related emissions by raising the energy of deep level defects, enhance photoluminescence (PL) accompanied by a longer excitation lifetime, as well as modulate the carrier type in CVD-grown MoSe$_2$ monolayer.\textsuperscript{23,25,26}

Beyond exploring the electron transport characteristics, deep understanding and manipulation of the phonon transport properties in 2D TMDs is crucial for their successful technological integration, specifically for heat management and hot spot minimization in high-performance solid-state electronic and optoelectronic devices as well as lattice thermal conductivity reduction for enhancing thermoelectric energy conversion efficiency (figure of merit). From the discovery of graphene,\textsuperscript{27–29}
which is composed of only one atomic layer of carbon, intensive investigations have been carried out to explore its heat conducting capability and the topic has been of a great interest for both fundamental science and practical relevance. On the other hand, to this date, only a limited number of experimental data exists in the literature on the thermal transport of monolayer 2D TMDs due mostly to increased complexity from the involved binary element system and experimental challenges in sample preparation and measurements. Recently, by utilizing micro-Raman thermometry, room-temperature thermal conductivity of 34.5 ± 1, 62.2 ± 1, and 84 ± 1 W m⁻¹ K⁻¹ was measured for MoS₂ and 59 ± 18 W m⁻¹ K⁻¹ for MoSe₂ monolayer flakes exfoliated from bulk crystal. Compared with experimental works, there is an increasing number of investigations based on theoretical and computational predictions in which room-temperature thermal conductivity of defect-free monolayer MoS₂ and MoSe₂ has been reported to be 83 ± 155 and 41 ± 54 W m⁻¹ K⁻¹, respectively. Furthermore, it has been recently predicted that vacancies can suppress the thermal conductivity of MoSe₂ monolayer. To shed light on the kind of nanostructured features required to tailor the transport characteristics in this promising layered material system, here, we employed a suspended microdevice on the basis of resistance thermometry to probe the temperature-dependent and intrinsic basal plane thermal conductivity of the pristine MoSe₂ and isoelectronic W-substituted Mo₁₋ₓWₓSe₂ monolayers synthesized by the CVD method. Experimental results reveal that even though substitutional W doping significantly suppresses the Se vacancy concentration in the Mo₀.₈₂W₀.₁₈Se₂ monolayer, its thermal conductivity remains intact. Our theoretical model is based on the first-principles density functional theory (DFT) and Boltzmann transport equations for quantitatively interpreting the experimental data and specifically for elucidating the influence of Se vacancies on the thermal conductivity of monolayer MoSe₂. Our results deepen our fundamental understanding of the underlying phonon transport mechanism in 2D TMDs and throw light on the overall possibility and scope of implementation of these promising atomically thin semiconductors as graphene alternatives.

**EXPERIMENTAL SECTION**

**Material Synthesis and Characterization.** The MoSe₂ and Mo₁₋ₓWₓSe₂ monolayers were grown on SiO₂/Si substrates using the CVD method, as reported previously, in which Se powder was evaporated to react with MoO₃ or mixture of MoO₃ and WO₃ in the presence of hydrogen gas. In this study, we choose Mo₀.₈₂W₀.₁₈Se₂ with a typical W concentration (x = 0.18, i.e., Mo₀.₈₂W₀.₁₈Se₂), as quantified in ref 23. The as-grown MoSe₂ and Mo₀.₈₂W₀.₁₈Se₂ monolayers show a similar triangular shape (with occasional bilayer islands), with typical lateral sizes between ~50 and 80 μm (Figure 1a). PL (Figure 1b) and Raman (Figure 1c) spectra are evidence for monolayer MoSe₂ and Mo₀.₈₂W₀.₁₈Se₂ (ref 26). As shown in Figure 1b, the PL intensity is greatly (by ~10 times) enhanced in Mo₀.₈₂W₀.₁₈Se₂ monolayers due to suppression of Se vacancies (by ~50%) as a result of isoelectronic W substitution. The Raman spectra indicate slight phonon hardening of Mo₀.₈₂W₀.₁₈Se₂ monolayers with little blueshift (by 2.2 cm⁻¹) of the A₁g vibration mode (Figure 1c).

**Thermal Measurements.** The suspended microdevice used to perform thermal transport measurements is shown in Figure 2a–c. The heart of the microdevice is two adjacent membranes made by low-stress silicon nitride (Si₃N₄). Each of these membranes was suspended by six long Si₃N₄ beams over a through-substrate hole. A serpentine platinum (Pt) line that serves as a heater and resistance thermometer (RT) was patterned on each membrane. Assembling the monolayer flake on the microdevice to bridge the two suspended membranes is one challenge in such measurements. To overcome this, we utilized a technique developed based on a poly(methyl methacrylate) (PMMA) carrier layer for the assembly of a single-walled carbon nanotube network in our previous work. After successful transfer of the flake on the membranes, the sample was immediately loaded into a high-vacuumed cryostat and to perform the thermal transport measurement, one membrane was Joule-heated and part of the heat was conducted through the suspended flake to the other membrane. The temperature rise in the two membranes was measured using the two Pt RTs. From the measured Joule heat and membrane temperatures, we obtained the total thermal resistance of the sample.

**RESULTS AND DISCUSSION**

A total of two pristine MoSe₂ monolayers, denoted as samples 1 and 2, and one doped Mo₀.₈₂W₀.₁₈Se₂ monolayer were successfully assembled on the microdevice using the PMMA transfer process, as illustrated in Figure 2a–c, respectively. The through-substrate hole under the two membranes allowed us to conduct transmission electron microscopy (TEM) characterization on the same suspended monolayer used for thermal measurements, which makes the correlation between the measured thermal conductivity and crystal structure information possible. Figure 2d–i shows the low- and high-resolution TEM images of the samples. After the PMMA transfer process, the viscous forces exerted on the assembled sample by the acetone during the drying process caused the samples to deform at the edges (Figure 2g,h). The dimensions and integrity of the sample are validated by the structural characterizations. The existence of PMMA residues reported for the Mo₀.₈₂W₀.₁₈Se₂ and h-BN, and graphene transferred with the same technique was also
observed on our samples, as seen in Figure 2d,e. Furthermore, an amorphous-like layer was observed in the high-resolution TEM images (Figure 2g–i) that originates from the PMMA residues and the oxidation of the samples, as it is known that the TMDs undergo the aging effect.50 The selected area electron beam diffraction (SAED) patterns were taken from two different regions on the suspended segment of the samples, one close to the edge (Figure 2j–l) and the other close to the middle part (Figure 2m–o). The SAED patterns close to the edge show more than one set of hexagonal Bragg reflections, which are in contrast
to the SAED patterns taken from the middle part of the sample. We believe this discrepancy is because at the edge, the sample is deformed due to the viscous forces acting on the sample upon the acetone drying process. This deformation of the flake at the edge of the sample causes it to fold on top of itself and thus generate more than one set of hexagonal diffraction patterns. On the other hand, the middle part of the sample is intact, hence the one set of hexagonal Bragg reflections that validates the single-crystallinity of our CVD-grown samples.

The measured thermal resistance of the sample ($R_t$) consists of contributions from (a) the intrinsic thermal resistance of the suspended segment of the flake between the two membranes, (b) the contact thermal resistance between the flake and two membranes ($R_c$), and (c) the internal thermal resistance of the two membranes caused by the nonuniform temperature distribution on the membranes ($R_{m0}$). To quantify each component of the measured total thermal resistance, we follow the procedure described in refs 47, 48, and 51 (see details of part I in the Supporting Information). Our calculation is sensitive to the interfacial thermal conductance ($g$) between the sample and the supporting membranes (Pt/SiNx in our case). Unfortunately, up to now, there is no reported temperature-dependent interfacial thermal conductance of the MoSe2 monolayer except at room temperature, which was measured on the SiO2 substrate in ref 37 to be 0.09 ± 0.03 MW m$^{-2}$ K$^{-1}$. In addition, interfacial thermal conductance of monolayer 2D TMDs is a topic of ongoing research to this date, with reported values that range with orders of magnitude difference. Specifically, the few reported experimental values of interfacial thermal conductance of monolayer MoS$_2$ at room temperature are $g = 1.94$, 0.44, and 14 MW m$^{-2}$ K$^{-1}$ in refs 36, 37, and 52, respectively. Because there is no current reliable data for interfacial thermal conductance between monolayer MoSe$_2$ and the Pt/SiNx of our device, we used the lowest and highest $g$ data of 2D materials in the literature that belong to few-layer h-BN$^{48}$ transferred onto suspended Pt/SiNx devices with a PMMA-assisted technique and few-layer graphene$^{53}$ encased in SiO$_2$, as shown in Figure 3a.

Figure 3b–d shows the $R_t$, $R_{m0}$, and $R_c$ calculated with $g$ of h-BN and graphene as a function of temperature for all samples. The $R_{m0}$ and $R_c$ are in agreement with previous results on suspended few-layer graphene$^{39}$ and MoS$_2$. Throughout the whole temperature range, the values of $R_{m0}$ are one order of magnitude smaller than those of $R_t$. At room temperature, the obtained $R_c/R_t$ ratios for MoSe$_2$ sample 1, sample 2, and Mo$_{0.82}$W$_{0.18}$Se$_2$ are, respectively, 20, 18, and 25% if using the few-layer h-BN interfacial conductance and 2.3, 2.4, and 3.6% if using the few-layer graphene interfacial conductance.

The thermal conductivity ($\kappa$) was then calculated from the intrinsic thermal resistance for both interfacial thermal conductance of few-layer h-BN and few-layer graphene by taking account of the dimensions of the suspended segment of the sample, as listed in Table 1. Figure 4 shows the intrinsic basal plane thermal conductivities as a function of temperature for all samples measured in this work. The higher $g$ value of graphene compared to that of h-BN results in a well thermally grounded flake to the membranes, smaller thermal contact resistance, and as a consequence, smaller calculated intrinsic thermal conductivities of the samples, as illustrated in Figure 4. For the two
The conductivity of the exfoliated MoSe2 monolayer has been measured by the optothermal Raman technique and reported to be $39 \pm 3.6$ and $28.4 \pm 3.5$ W m$^{-1}$ K$^{-1}$ for g of h-BN and $32.4 \pm 3.5$ W m$^{-1}$ K$^{-1}$ for g of graphene at 300 K. At the same temperature, thermal conductivity of the exfoliated MoSe2 monolayer has been measured with diode-laser heating and reported in ref 37 can be attributed to the higher vacancy concentration in our CVD-grown samples compared to their exfoliated counterpart, as will be explained later. Similarly, thermal conductivity of suspended CVD graphene was found to be lower than that in exfoliated samples. For the Mo$_{0.82}$W$_{0.18}$Se$_2$ monolayer with 0.5% Se vacancy concentration at 300 K is 27.4 and 21.0 W m$^{-1}$ K$^{-1}$, respectively. They are close to the experimental results, i.e., $\kappa = 28.7 \pm 3.6$ and $28.4 \pm 3.5$ W m$^{-1}$ K$^{-1}$ for MoSe$_2$ monolayer and $\kappa = 23.2 \pm 3.7$ W m$^{-1}$ K$^{-1}$ for graphene at 300 K. These results indicate that there is an ~15% reduction in the thermal conductivity due to doping, even though substitutional doping of MoSe$_2$ monolayer by W atoms considerably suppresses the Se vacancy concentration. As will be discussed later, this is not the contributing factor in the thermal conductivity reduction but rather the difference in the sample lengths (1 μm vs 0.6 μm for the doped sample). Furthermore, both pristine and W-doped MoSe$_2$ monolayers exhibit a nanostructured behavior at low temperatures, i.e., monotonically increasing thermal conductivity with the temperature. This can be understood by the circumstance that phonon scattering dominates over defects and phonon scattering at these temperatures, as will be elucidated later.

To obtain a deeper insight into the phonon transport processes in our samples and quantitatively interpret the experimental data, we modeled pristine MoSe$_2$ and W-doped Mo$_{0.82}$W$_{0.18}$Se$_2$ with different levels of Se vacancies. Our approach is based on the first-principles density functional theory (DFT) and Boltzmann transport equations (BTEs) (see details of part II in the Supporting Information). The iterative solution of the BTE is used to predict the thermal conductivity of MoSe$_2$ and Mo$_{0.82}$W$_{0.18}$Se$_2$ using the second-order harmonic and third-order anharmonic interatomic force constants obtained from the DFT calculations. In addition, a model for estimating the effect of defects on phonon properties of the monolayer MoSe$_2$ is developed by incorporating the phonon scattering corresponding to the removal of the mass of atoms and the change of force constants between the under-coordinated atoms near the vacancies (see details in the Supporting Information). In addition, the effect of sample size on the thermal conductivity is also taken into account.

Figure 5a shows that the computed thermal conductivities for the 1 μm long MoSe$_2$ monolayer with 4% Se vacancy concentration and 0.5 μm long Mo$_{0.82}$W$_{0.18}$Se$_2$ monolayer with 2% Se vacancy concentration at 300 K are 27.4 and 21.0 W m$^{-1}$ K$^{-1}$, respectively. They are close to the experimental results, i.e., $\kappa = 28.7 \pm 3.6$ and $28.4 \pm 3.5$ W m$^{-1}$ K$^{-1}$ for MoSe$_2$ monolayer and $\kappa = 23.2 \pm 3.7$ W m$^{-1}$ K$^{-1}$ for the Mo$_{0.82}$W$_{0.18}$Se$_2$ monolayer, respectively, calculated on the basis of g of graphene. However, the trend of the thermal conductivity with increasing temperature from our simulations does not match with that from the measurements. First, the temperature corresponding to peak thermal conductivity from the simulations is much lower than that of the experiment. Second, Figure 5a indicates that the thermal conductivity predicted by simulations decreases sharply as the temperature increases, which is due to the dominance of Umklapp scattering at high temperatures. However, in the experiment, the shape of the temperature-dependent thermal conductivity becomes much flatter than that in the simulation as the temperature increases. One reason for the mismatch between the experimental and simulation results is the strong phonon scattering caused by the impurities (residual PMMA and native oxide layers) in the samples considered. The residual polymer and native oxide layers, as surface disorders, act essentially as a support layer that can suppress the ZA modes in the monolayer MoSe$_2$ and W-doped MoSe$_2$ due to the

![Figure 4](image_url). Intrinsic basal plane thermal conductivity of the samples as a function of temperature calculated with g of graphene for MoSe$_2$ sample 1 (filled triangles), MoSe$_2$ sample 2 (filled squares), Mo$_{0.82}$W$_{0.18}$Se$_2$ (filled circles), and g of h-BN for MoSe$_2$ sample 1 (unfilled triangles), MoSe$_2$ sample 2 (unfilled squares), and Mo$_{0.82}$W$_{0.18}$Se$_2$ (unfilled circles).
Figure 5. Se vacancy and sample length-dependent thermal conductivity of monolayer MoSe₂ and Mo₀.82W₀.18Se₂. (a) The monolayer MoSe₂ with 4% Se vacancy and Mo₀.82W₀.18Se₂ with 2% Se vacancy for different sample lengths. The experimental data processed with g of graphene for all samples is also shown. The inset shows the experimentally observed thermal conductivity scaling with temperature at low temperatures. (b) The monolayer MoSe₂ with 1, 2, and 4% Se vacancy and Mo₀.82W₀.18Se₂ with 1, 2, and 4% Se vacancy (1 μm sample length). The inset shows the calculated thermal conductivity of the MoSe₂ with 4% Se vacancy and Mo₀.82W₀.18Se₂ with 2% Se vacancy scaling, with temperature at low temperatures.

In our samples, but PMMA residue and oxidation due to aging is evident in the TEM characterization that affect the scattering of phonons of varying frequencies.

Furthermore, even though the W doping suppresses the Se-vacant sites by 50% (from 4 to 2%), the thermal conductivity of monolayer MoSe₂ and W-doped MoSe₂ is still similar in both measurements and simulations. We calculated the thermal conductivities of the pristine MoSe₂ and Mo₀.82W₀.18Se₂ monolayer without defects as 55.1 and 51.0 W m⁻¹ K⁻¹, respectively. As depicted in Figure 5b, results indicate that the existence of 1, 2, and 4% Se vacancy concentrations decrease the thermal conductivity of the monolayer MoSe₂ by 11.2, 23.4, and 46.2%, respectively, at the room temperature, whereas that of the Mo₀.82W₀.18Se₂ monolayer by 27.0, 51.0, and 72.2%, respectively. The W-doped MoSe₂ have a stronger sensitivity to the defects than pristine MoSe₂. As the mass of the W atom is larger than that of the Mo atom, the missing Se atom at a vacancy site results in a larger mass difference and kinetic energy and potential energy difference. This further enhances the phonon scattering due to the defects and results in the suppression of the thermal conductivity.

CONCLUSIONS

In summary, we report the impact of isoelectronic W doping and Se vacancies on the thermal conductivity of the suspended MoSe₂ monolayer grown by CVD. Experimental observations reveal that even though the isoelectronic substitution of the W atoms for Mo atoms in the CVD-grown Mo₀.82W₀.18Se₂ monolayer reduces the Se vacancy concentration by 50% compared to that found in the MoSe₂ monolayer, the thermal conductivity remains almost unchanged in a wide temperature range. This was further confirmed by calculations based on first-principles density functional theory (DFT) and the Boltzmann transport equations (BTEs). However, there is a mismatch between the experimental and simulation results for the trend of temperature dependency of thermal conductivity. This discrepancy is attributed to the strong phonon scattering caused by the residual PMMA and oxide layers on the monolayer flakes that essentially act as a support layer and suppress the ZA mode, which is not fully captured in the calculations. Interestingly, we found that the phonon transport in the W-doped MoSe₂ is more

scattering with the support layer (~impurities). This reduces the maximum value of the thermal conductivity and increases the temperature where the peak is located. In addition, the diffuse phonon-surface scattering caused by the residual polymer and native oxide layers is not temperature sensitive, which flattens the thermal conductivity curve at the high temperatures and the sensitivity of the three-phonon process with temperature does not show up in Figure 5b.

The sample size also has a significant influence on the thermal conductivity of the monolayer MoSe₂ as shown in Figure 5a. As the length of the sample decreases, the phonon boundary scattering becomes dominant and the phonon-phonon scattering becomes relatively weak, which flattens the temperature-dependent thermal conductivity at high temperature. The size effect can be ignored if the sample size is larger than 10 μm because the maximum phonon mean free path in MoSe₂ is around 10 μm.

As illustrated in the insert of Figure 5a, the experimentally observed thermal conductivity for the 1 μm long MoSe₂ monolayer with 4% Se vacancy concentration follows T⁻¹ at T < 100 K and that of the 0.6 μm long Mo₀.82W₀.18Se₂ monolayer with 2% Se vacancy concentration follows T⁰.⁶⁵ at T < 200 K. Theoretical results show temperature dependence as T⁻¹.⁷⁸–¹.⁸ at T < 20 K for 0.5–1.5 μm long MoSe₂ monolayer samples, considering the effects of boundary and defects scattering. W doping suppresses the temperature dependence to T⁻¹.⁷¹–¹.⁹, which is in good agreement with the experimental observation, T⁰.⁶⁵. These values are different from those of theoretical three-dimensional (3D) crystals, where at very low temperatures, κ ∝ T⁰ due to weak anharmonic phonon scattering and heat capacity ∝ T⁰ due to the linear acoustic phonon dispersion (the Debye model) at low frequencies and the 3D density of states. However, the existence of the quadratic flexure (out-of-plane) phonon modes in 2D materials and the 2D density of states can lead to a different scaling law of thermal conductivity at low temperatures.

A similar trend was also observed in a previous work on monolayer MoSe₂ where such a power law was attributed to the contribution of the quadratic phonon branch and the existence of grain boundaries and surface disorders, such as PMMA residue and oxide layers due to sample aging. The structural analysis did not show any evidence of grain boundaries
sensitive to the Se-vacant sites than that in pristine MoSe₂ due to the difference in their potential energy. Also, the prominent role of boundary scattering over defects and phonon–phonon scattering at low temperatures for both material systems is evident by the monotonically increasing thermal conductivity with temperature at these temperatures. Overall, these results demonstrate the paramount structure–phonon transport link in 2D TMDs paving the route of their successful integration into modern solid-state devices.

**ASSOCIATED CONTENT**

Supporting Information
The Supporting Information is available free of charge on the ACS Publications website at DOI: 10.1021/acsami.7b14310.

More detailed information about the thermal measurements, COMSOL simulation, DFT and BTE theoretical calculations (PDF)

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**Notes**
The authors declare no competing financial interest.

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